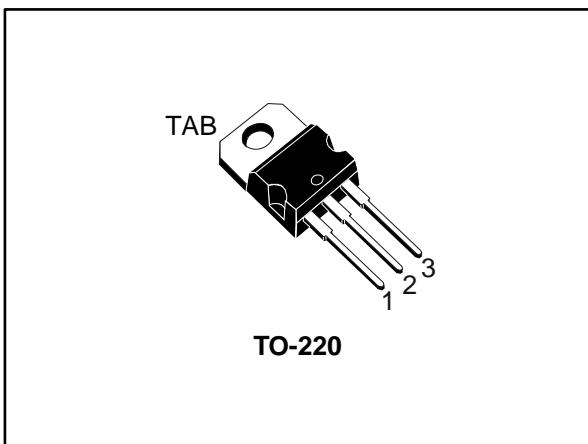
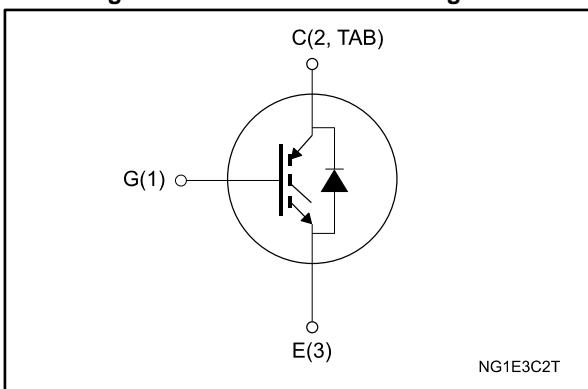


## Trench gate field-stop IGBT M series, 650 V, 15 A low-loss in a TO-220 package

Datasheet - production data



**Figure 1: Internal schematic diagram**



### Features

- 6  $\mu$ s of short-circuit withstand time
- $V_{CE(sat)} = 1.55$  V (typ.) @  $I_C = 15$  A
- Tight parameter distribution
- Safer paralleling
- Positive  $V_{CE(sat)}$  temperature coefficient
- Low thermal resistance
- Soft and very fast recovery antiparallel diode
- Maximum junction temperature:  $T_J = 175$  °C

### Applications

- Motor control
- UPS
- PFC
- General purpose inverter

### Description

This device is an IGBT developed using an advanced proprietary trench gate field-stop structure. The device is part of the M series IGBTs, which represent an optimal balance between inverter system performance and efficiency where low-loss and short-circuit functionality are essential. Furthermore, the positive  $V_{CE(sat)}$  temperature coefficient and tight parameter distribution result in safer paralleling operation.

**Table 1: Device summary**

Order code	Marking	Package	Packing
STGP15M65DF2	G15M65DF2	TO-220	Tube

**Contents**

<b>1</b>	<b>Electrical ratings .....</b>	<b>3</b>
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# 1 Electrical ratings

**Table 2: Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{CES}$	Collector-emitter voltage ( $V_{GE} = 0$ V)	650	V
$I_C$	Continuous collector current at $T_C = 25$ °C	30	A
	Continuous collector current at $T_C = 100$ °C	15	A
$I_{CP}^{(1)}$	Pulsed collector current	60	A
$V_{GE}$	Gate-emitter voltage	$\pm 20$	V
$I_F$	Continuous forward current at $T_C = 25$ °C	30	A
$I_F$	Continuous forward current at $T_C = 100$ °C	15	A
$I_{FP}^{(1)}$	Pulsed forward current	60	A
$P_{TOT}$	Total dissipation at $T_C = 25$ °C	136	W
$T_{STG}$	Storage temperature range	- 55 to 150	°C
$T_J$	Operating junction temperature range	- 55 to 175	°C

**Notes:**

(1)Pulse width limited by maximum junction temperature.

**Table 3: Thermal data**

Symbol	Parameter	Value	Unit
$R_{thJC}$	Thermal resistance junction-case IGBT	1.1	°C/W
$R_{thJC}$	Thermal resistance junction-case diode	2.08	°C/W
$R_{thJA}$	Thermal resistance junction-ambient	62.5	°C/W

## 2 Electrical characteristics

$T_J = 25^\circ\text{C}$  unless otherwise specified.

Table 4: Static characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)CES}$	Collector-emitter breakdown voltage	$V_{GE} = 0 \text{ V}$ , $I_C = 250 \mu\text{A}$	650			V
$V_{CE(\text{sat})}$	Collector-emitter saturation voltage	$V_{GE} = 15 \text{ V}$ , $I_C = 15 \text{ A}$		1.55	2.0	V
		$V_{GE} = 15 \text{ V}$ , $I_C = 15 \text{ A}$ $T_J = 125^\circ\text{C}$		1.9		
		$V_{GE} = 15 \text{ V}$ , $I_C = 15 \text{ A}$ $T_J = 175^\circ\text{C}$		2.1		
$V_F$	Forward on-voltage	$I_F = 15 \text{ A}$		1.7	2.6	V
		$I_F = 15 \text{ A}$ $T_J = 125^\circ\text{C}$		1.5		V
		$I_F = 15 \text{ A}$ $T_J = 175^\circ\text{C}$		1.4		V
$V_{GE(\text{th})}$	Gate threshold voltage	$V_{CE} = V_{GE}$ , $I_C = 500 \mu\text{A}$	5	6	7	V
$I_{CES}$	Collector cut-off current	$V_{GE} = 0 \text{ V}$ , $V_{CE} = 650 \text{ V}$			25	$\mu\text{A}$
$I_{GES}$	Gate-emitter leakage current	$V_{CE} = 0 \text{ V}$ , $V_{GE} = \pm 20 \text{ V}$			$\pm 250$	$\mu\text{A}$

Table 5: Dynamic characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{ies}$	Input capacitance	$V_{CE} = 25 \text{ V}$ , $f = 1 \text{ MHz}$ , $V_{GE} = 0 \text{ V}$	-	1250	-	pF
$C_{oes}$	Output capacitance		-	80	-	pF
$C_{res}$	Reverse transfer capacitance		-	25	-	pF
$Q_g$	Total gate charge	$V_{CC} = 520 \text{ V}$ , $I_C = 15 \text{ A}$ , $V_{GE} = 0 \text{ to } 15 \text{ V}$ (see <a href="#">Figure 30: "Gate charge test circuit"</a> )	-	45	-	nC
$Q_{ge}$	Gate-emitter charge		-	11	-	nC
$Q_{gc}$	Gate-collector charge		-	15	-	nC

Table 6: IGBT switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{CE} = 400 \text{ V}, I_C = 15 \text{ A}, V_{GE} = 15 \text{ V}, R_G = 12 \Omega$ (see <a href="#">Figure 29: "Test circuit for inductive load switching"</a> )		24	-	ns
$t_r$	Current rise time			7.8	-	ns
$(di/dt)_{on}$	Turn-on current slope			1570	-	A/ $\mu\text{s}$
$t_{d(off)}$	Turn-off delay time			93	-	ns
$t_f$	Current fall time			106	-	ns
$E_{on}^{(1)}$	Turn-on switching energy			0.09	-	$\mu\text{J}$
$E_{off}^{(2)}$	Turn-off switching energy			0.45	-	$\mu\text{J}$
$E_{ts}$	Total switching energy			0.54	-	$\mu\text{J}$
$t_{d(on)}$	Turn-on delay time	$V_{CE} = 400 \text{ V}, I_C = 15 \text{ A}, R_G = 15 \Omega, V_{GE} = 15 \text{ V}, T_J = 175 \text{ }^\circ\text{C}$ (see <a href="#">Figure 29: "Test circuit for inductive load switching"</a> )		24.8	-	ns
$t_r$	Current rise time			9.2	-	ns
$(di/dt)_{on}$	Turn-on current slope			1300	-	A/ $\mu\text{s}$
$t_{d(off)}$	Turn-off delay time			96	-	ns
$t_f$	Current fall time			169	-	ns
$E_{on}^{(1)}$	Turn-on switching energy			0.22	-	$\mu\text{J}$
$E_{off}^{(2)}$	Turn-off switching energy			0.61	-	$\mu\text{J}$
$E_{ts}$	Total switching energy			0.83	-	$\mu\text{J}$
$t_{sc}$	Short-circuit withstand time	$V_{CC} \leq 400 \text{ V}, V_{GE} = 15 \text{ V}, T_{Jstart} = 150 \text{ }^\circ\text{C}$	6		-	$\mu\text{s}$
		$V_{CC} \leq 400 \text{ V}, V_{GE} = 13 \text{ V}, T_{Jstart} = 150 \text{ }^\circ\text{C}$	10		-	

**Notes:**

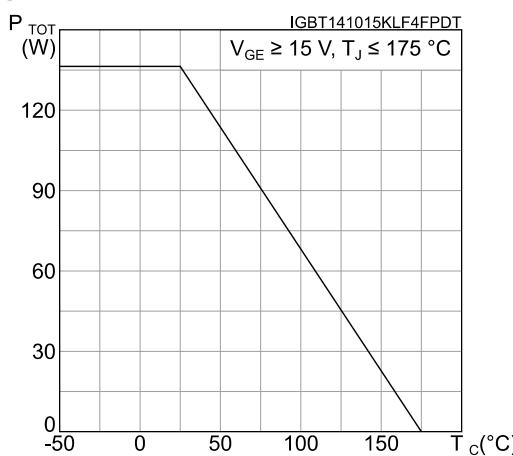
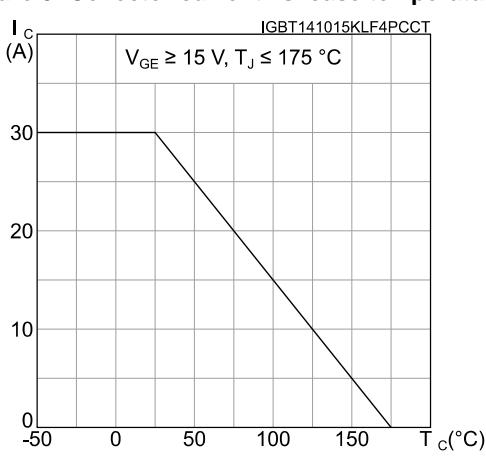
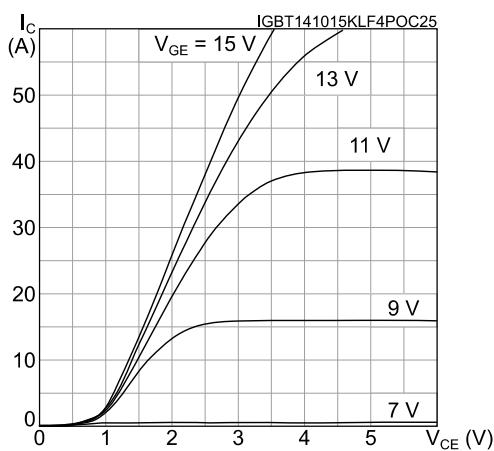
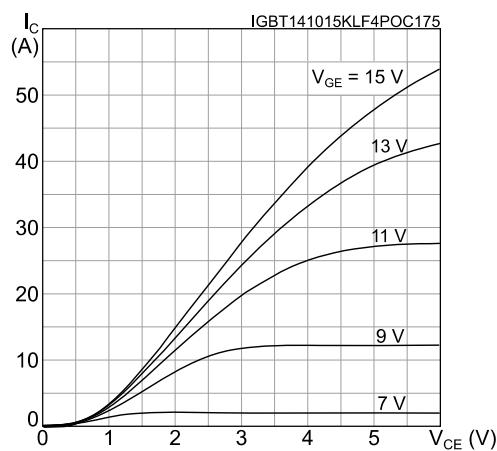
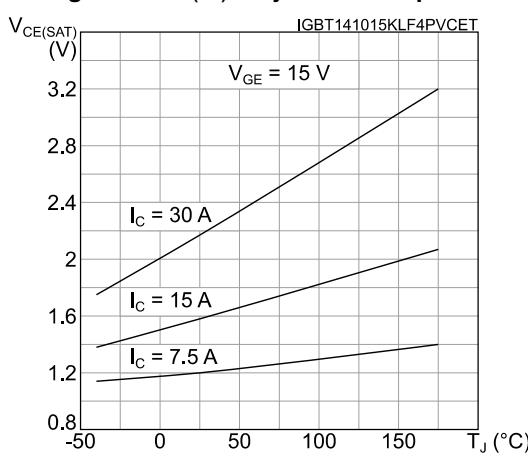
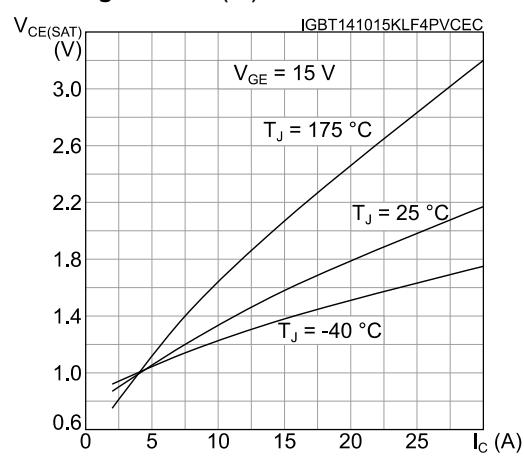
(1) Including the reverse recovery of the diode.

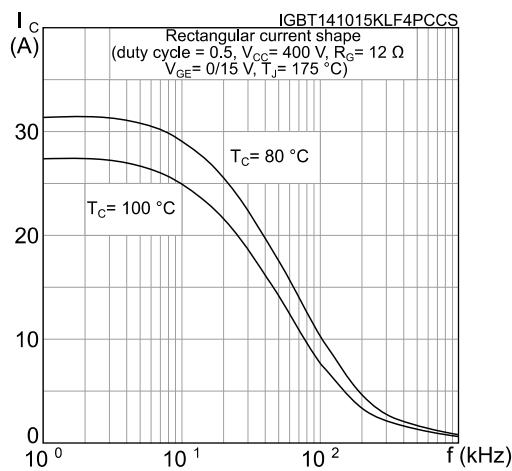
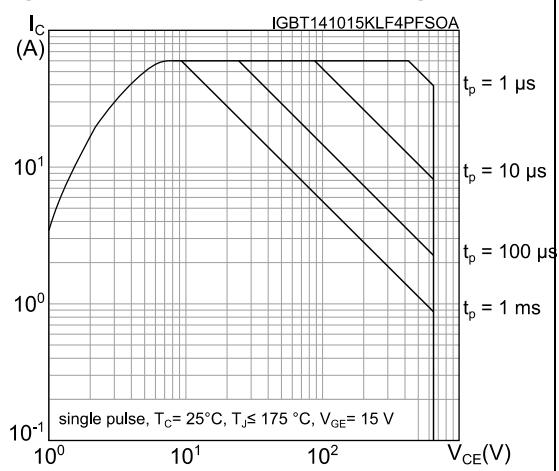
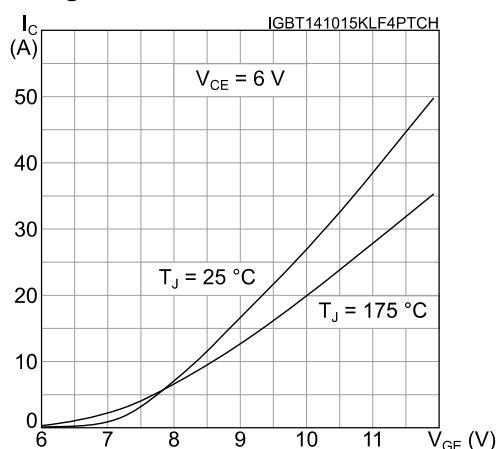
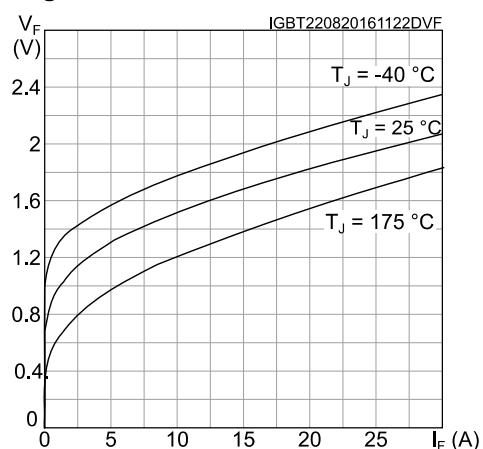
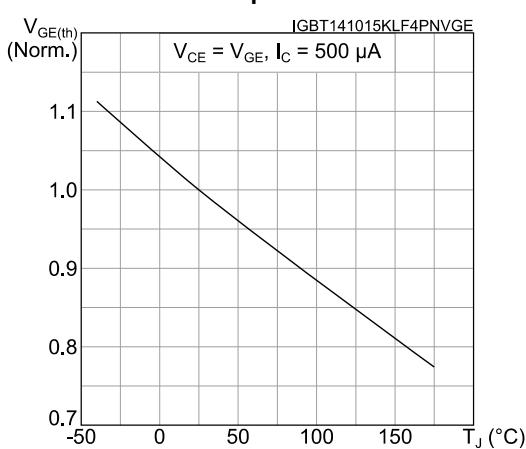
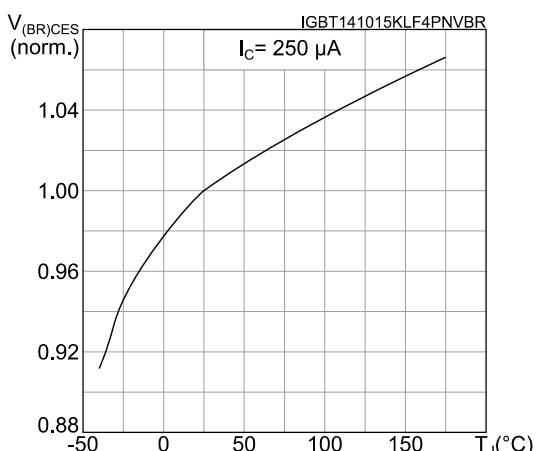
(2) Including the tail of the collector current.

Table 7: Diode switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{rr}$	Reverse recovery time	$I_F = 15 \text{ A}, V_R = 400 \text{ V}, V_{GE} = 15 \text{ V}, di/dt = 1000 \text{ A}/\mu\text{s}$ (see <a href="#">Figure 29: "Test circuit for inductive load switching"</a> )	-	142	-	ns
$Q_{rr}$	Reverse recovery charge		-	525	-	nC
$I_{rrm}$	Reverse recovery current		-	13.4	-	A
$dI_{rr}/dt$	Peak rate of fall of reverse recovery current during $t_b$		-	790	-	A/ $\mu\text{s}$
$E_{rr}$	Reverse recovery energy		-	64	-	$\mu\text{J}$
$t_{rr}$	Reverse recovery time		-	241	-	ns
$Q_{rr}$	Reverse recovery charge	$I_F = 15 \text{ A}, V_R = 400 \text{ V}, V_{GE} = 15 \text{ V}, di/dt = 1000 \text{ A}/\mu\text{s}, T_J = 175 \text{ }^\circ\text{C}$ (see <a href="#">Figure 29: "Test circuit for inductive load switching"</a> )	-	1690	-	nC
$I_{rrm}$	Reverse recovery current		-	20	-	A
$dI_{rr}/dt$	Peak rate of fall of reverse recovery current during $t_b$		-	420	-	A/ $\mu\text{s}$
$E_{rr}$	Reverse recovery energy		-	176	-	$\mu\text{J}$

## 2.1 Electrical characteristics (curves)

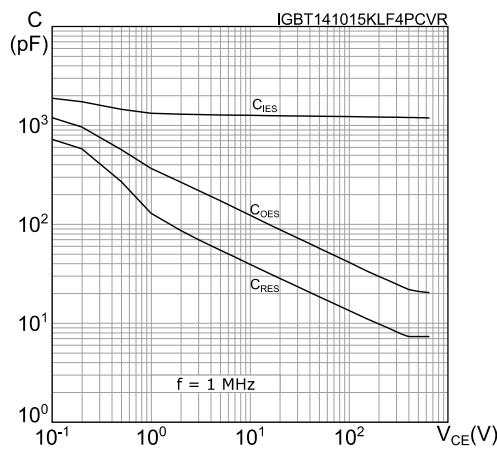
**Figure 2: Power dissipation vs. case temperature****Figure 3: Collector current vs. case temperature****Figure 4: Output characteristics ( $T_J = 25 \text{ }^{\circ}\text{C}$ )****Figure 5: Output characteristics ( $T_J = 175 \text{ }^{\circ}\text{C}$ )****Figure 6:  $V_{CE(\text{sat})}$  vs. junction temperature****Figure 7:  $V_{CE(\text{sat})}$  vs. collector current**

**Figure 8: Collector current vs. switching frequency****Figure 9: Forward bias safe operating area****Figure 10: Transfer characteristics****Figure 11: Diode VF vs. forward current****Figure 12: Normalized  $V_{GE(\text{th})}$  vs. junction temperature****Figure 13: Normalized  $V_{(BR)CES}$  vs. junction temperature**

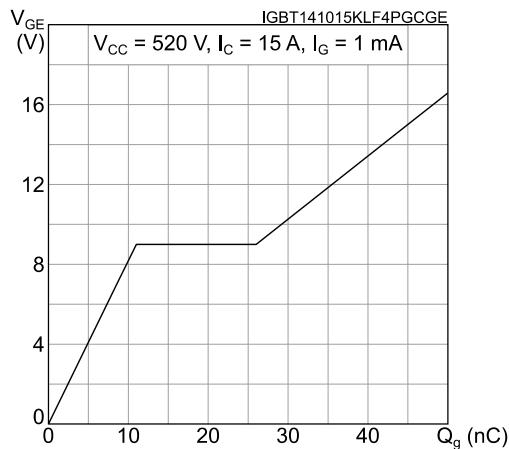
## Electrical characteristics

STGP15M65DF2

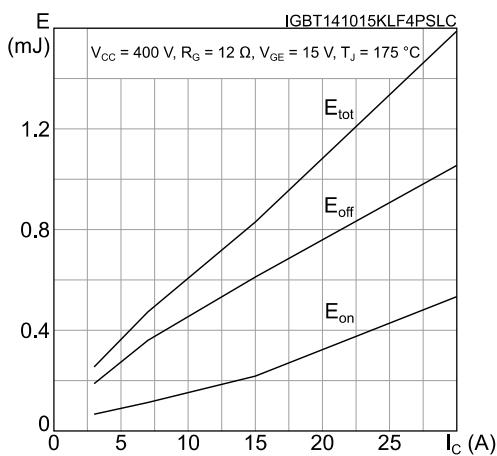
**Figure 14: Capacitance variations**



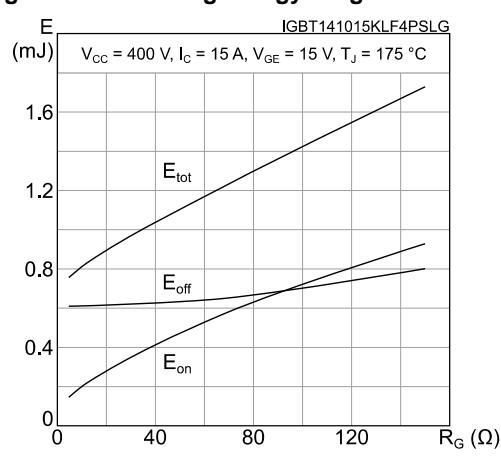
**Figure 15: Gate charge vs. gate-emitter voltage**



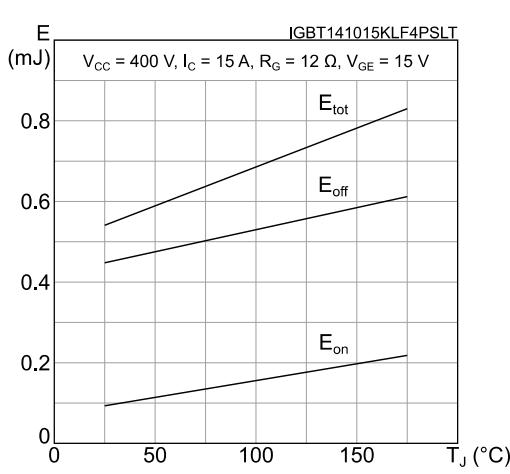
**Figure 16: Switching energy vs. collector current**



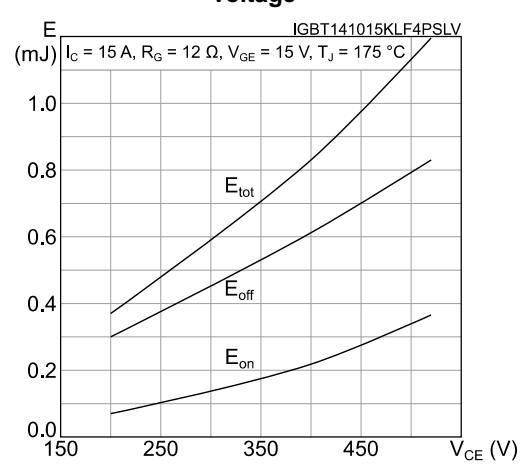
**Figure 17: Switching energy vs. gate resistance**



**Figure 18: Switching energy vs. temperature**



**Figure 19: Switching energy vs. collector-emitter voltage**



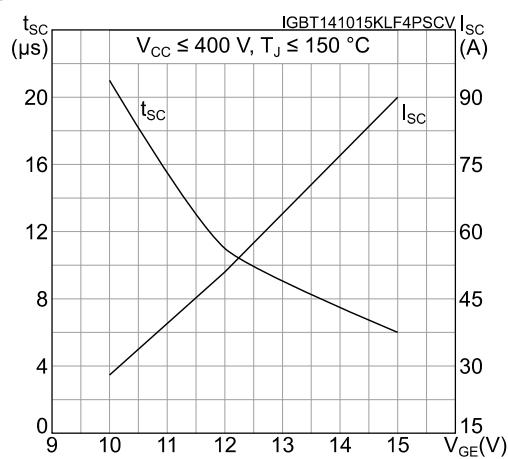
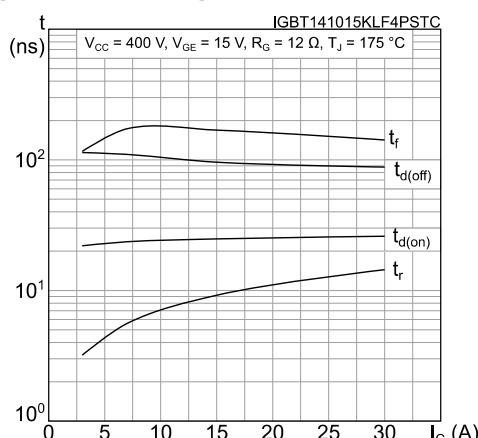
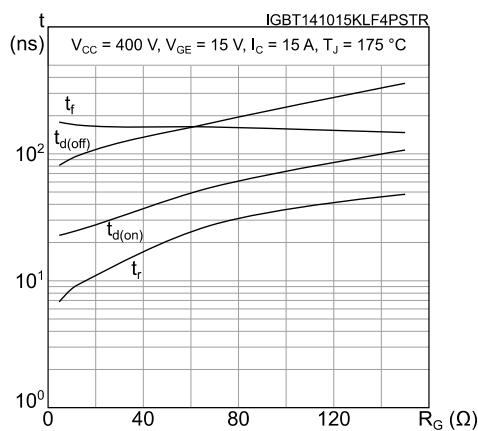
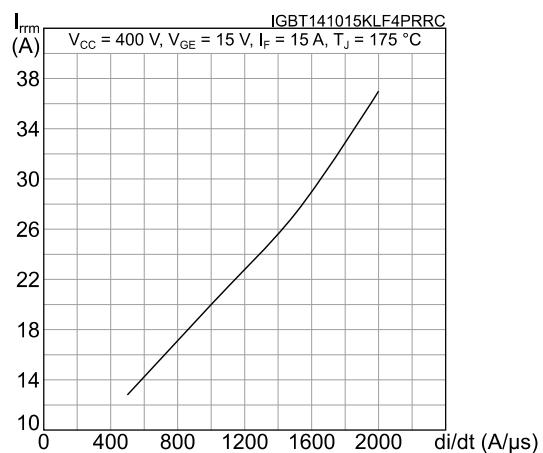
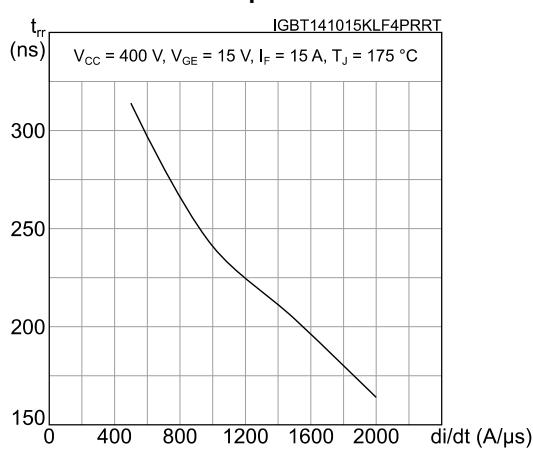
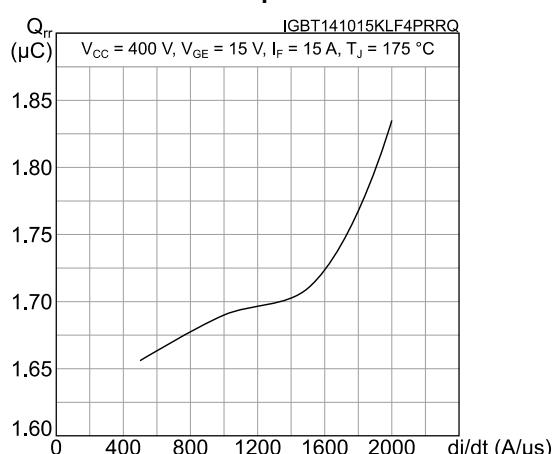
**Figure 20: Short-circuit time and current vs.  $V_{GE}$** **Figure 21: Switching times vs. collector current****Figure 22: Switching times vs. gate resistance****Figure 23: Reverse recovery current vs. diode current slope****Figure 24: Reverse recovery time vs. diode current slope****Figure 25: Reverse recovery charge vs. diode current slope**

Figure 26: Reverse recovery energy vs. diode current slope

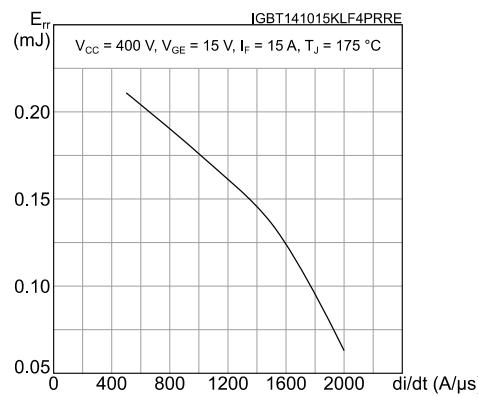


Figure 27: Thermal impedance for IGBT

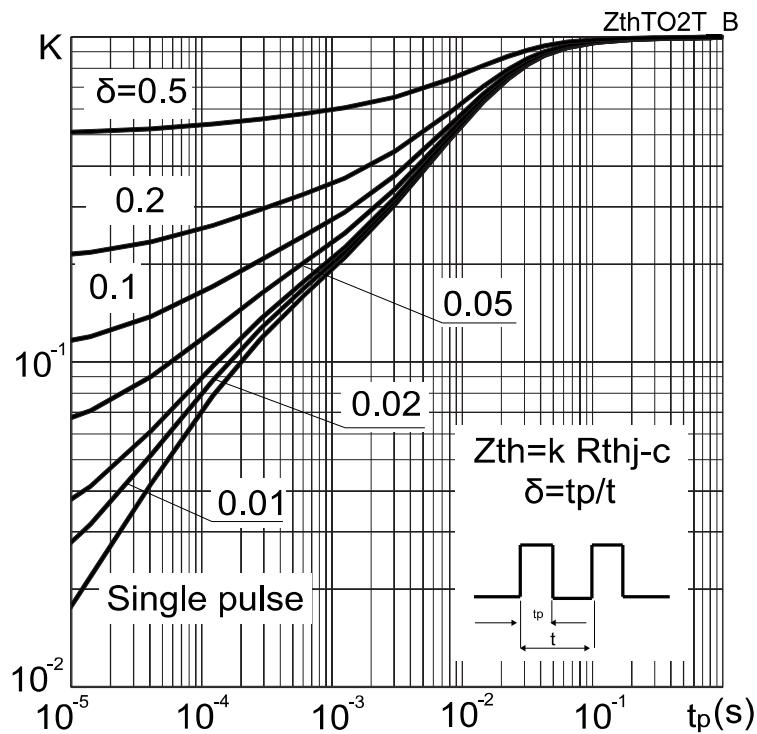
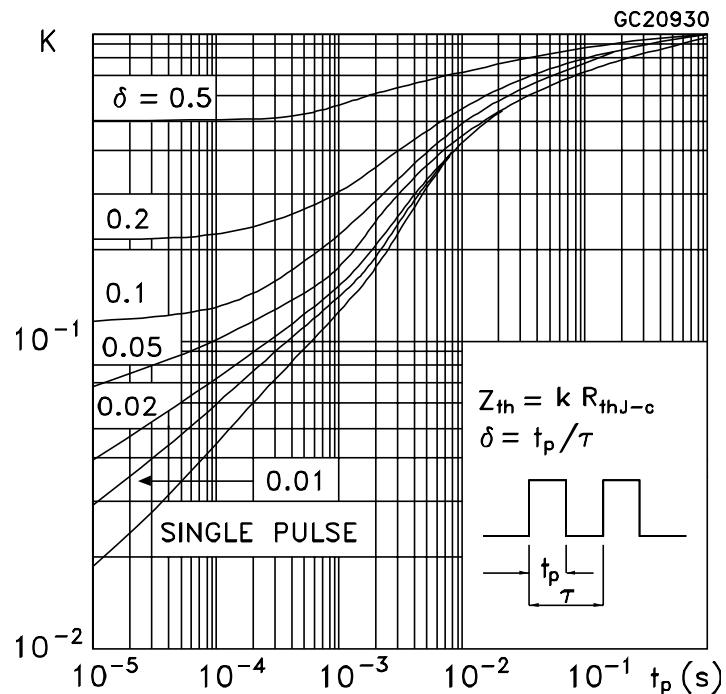
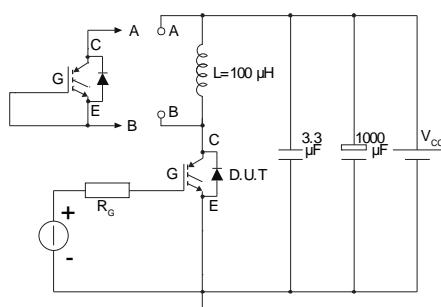


Figure 28: Thermal impedance for diode



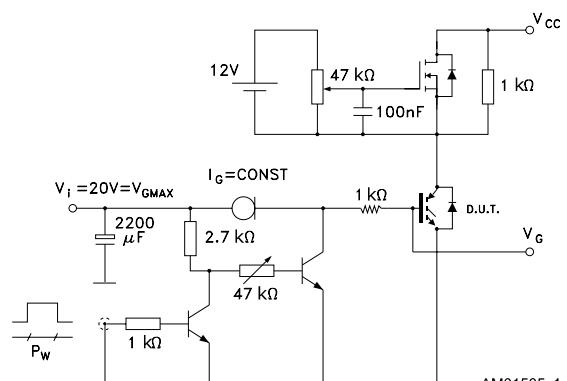
### 3 Test circuits

**Figure 29: Test circuit for inductive load switching**



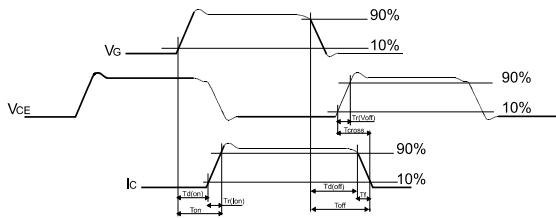
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**Figure 30: Gate charge test circuit**



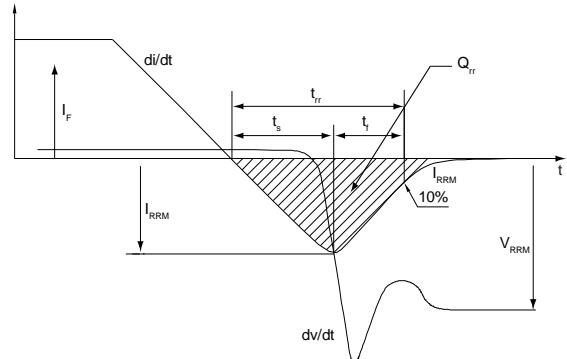
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**Figure 31: Switching waveform**



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**Figure 32: Diode reverse recovery waveform**



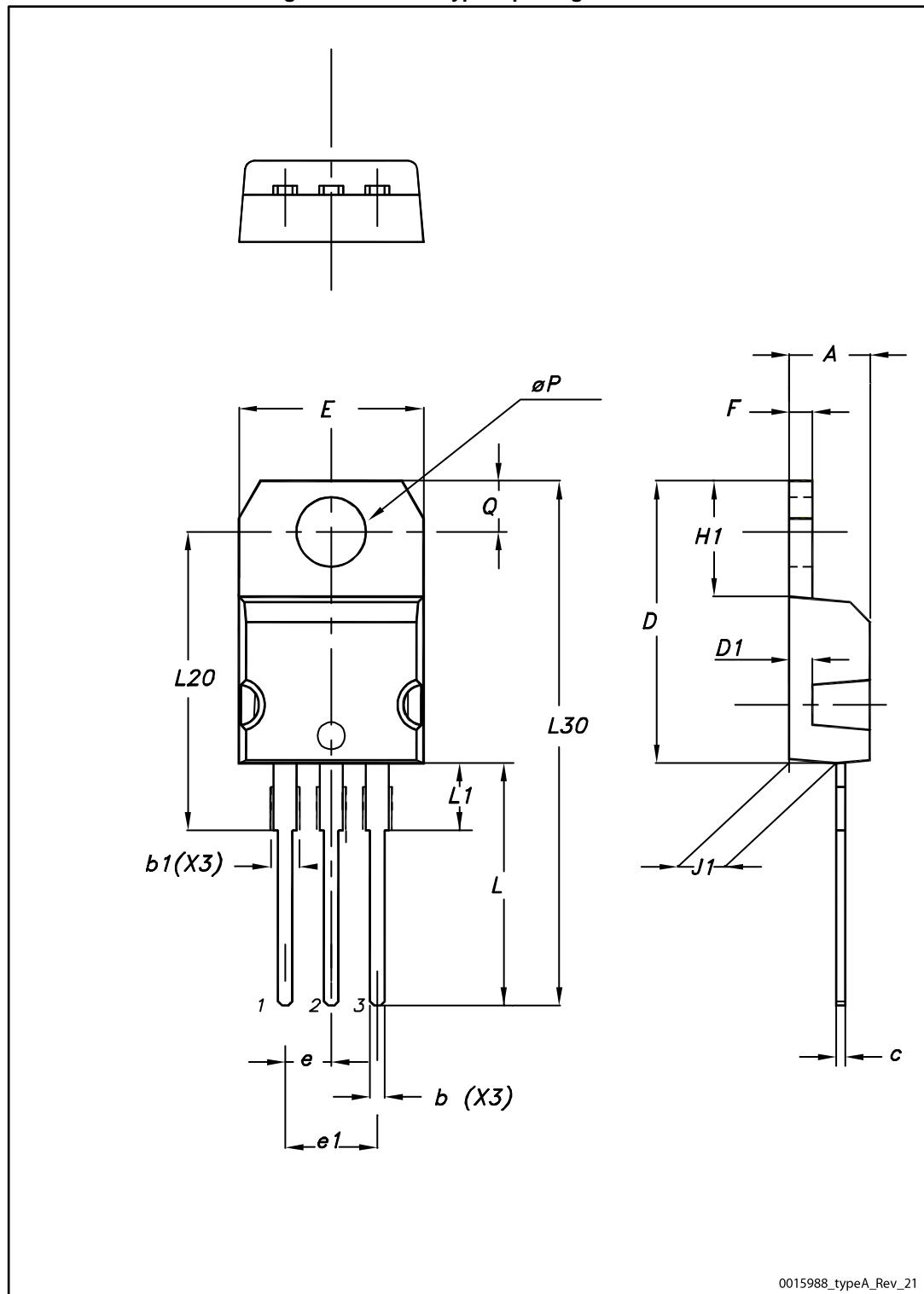
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## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

## 4.1 TO-220 type A package information

Figure 33: TO-220 type A package outline



**Table 8: TO-220 type A package mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
b	0.61		0.88
b1	1.14		1.55
c	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10.00		10.40
e	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13.00		14.00
L1	3.50		3.93
L20		16.40	
L30		28.90	
øP	3.75		3.85
Q	2.65		2.95

## 5 Revision history

Table 9: Document revision history

Date	Revision	Changes
14-Oct-2015	1	First release.
13-Nov-2015	2	Document status promoted from preliminary to production data.
22-Aug-2016	3	Updated Table 2: "Absolute maximum ratings" and Table 6: "IGBT switching characteristics (inductive load)". Updated Figure 16: "Switching energy vs. collector current", Figure 17: "Switching energy vs. gate resistance", Figure 18: "Switching energy vs. temperature" and Figure 19: "Switching energy vs. collector emitter voltage". Changed Figure 11: "Diode VF vs. forward current".
28-Apr-2017	4	Modified: title, features and applications on cover page. Modified <a href="#">Table 4: "Static characteristics"</a> , <a href="#">Table 5: "Dynamic characteristics"</a> , <a href="#">Table 7: "Diode switching characteristics (inductive load)"</a> . Minor text changes.